

Notice of References CitedApplication/Control No.
09/811,904Applicant(s)/Patent Under
Reexamination
TORTI ET AL.Examiner
Zia R. HashmiArt Unit
2881

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
✓	U	Mack et al. "Gas Cluster Ion Beam Size Diagnostics and Workpiece Processing", pub. no: US/2002/0070361 A1, published June 13, 2002.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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